

Search Notes**Application/Control No.**

10/651,049

Examiner

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Applicant(s)/Patent under Reexamination

GONTIN ET AL.

Art Unit

2877

SEARCHED

Class	Subclass	Date	Examiner
356	488	8/1/2005	MJD
356	494	8/1/2005	MJD
356	512	8/1/2005	MJD
356	521	8/1/2005	MJD
250	237G	8/1/2005	MJD
356	488	9/28/2005	MJD
356	494	9/28/2005	MJD
356	512	9/28/2005	MJD
356	521	9/28/2005	MJD
250	237G	9/28/2005	MJD

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
356	521 Pubs	8/2/2005	MJD
356	512 Pubs	8/2/2005	MJD

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
All of 356 and waveform and second adj grating	8/1/2005	MJD
All of 356 and waveform and reticle adj stage and wafer adj stage	8/1/2005	MJD
All of 356 and lateral adj shearing adj interferometry	8/1/2005	MJD
All of 356 and rough adj grating	8/2/2005	MJD
All of 356 and random\$ near grating and parallel	8/2/2005	MJD
All of 356 and nonuniform adj grating and parallel	8/2/2005	MJD
Updated search after RCE of subclasses	9/28/2005	MJD